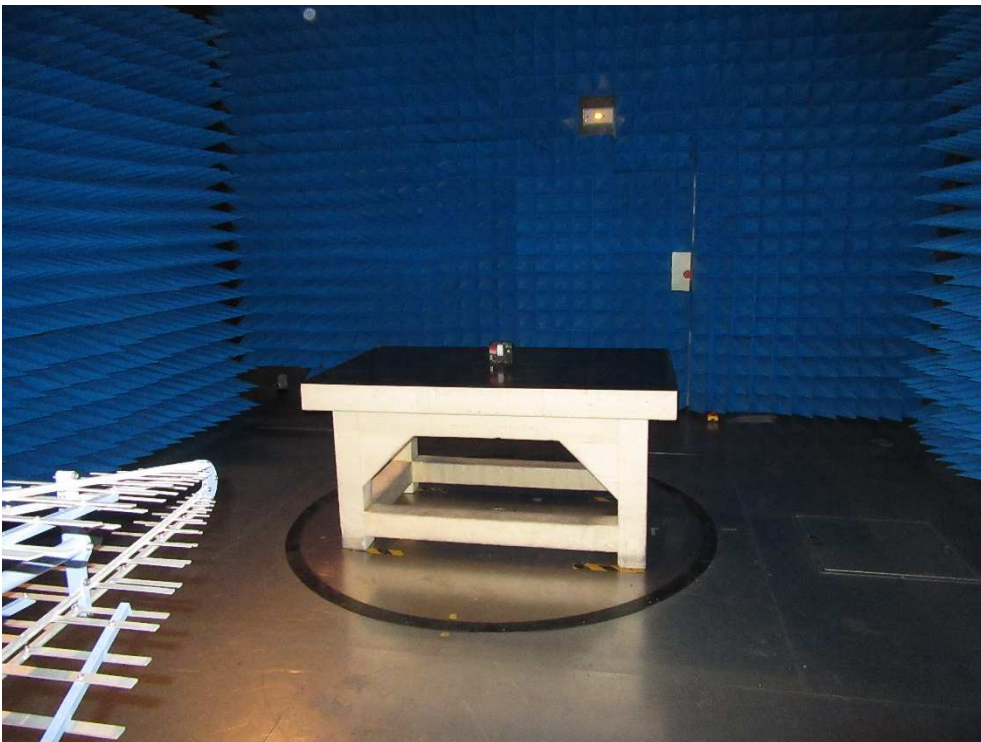


1 Radiated tests below 30 MHz (e.g. Emission mask, Spurious Em.)



2 Radiated emissions measurements from 30 MHz to 1000 MHz

Test set-up photo:





For detailed product photos see:

[DK_Photos-GAT Lock 6010 F 3-1_EN_V010001.pdf](#)

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